

Device simulation Lab :Assignment 5

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EE22M308

Lab No:5

Software: Matlab 2022a

Numerical solution of Poisson's equation with Maxwell-Boltzmann distribution of carrier density:

Qa. Assuming electrons as the only type of carriers and an undoped semiconductor, write the appropriate form of Poisson's equation for electrostatics (assume that the current is zero, and Maxwell-Boltzmann statistics for carriers).

Ans:

Ans: - (a)

Write Poisson's eqn form:-

$$\nabla^2 V = - \frac{\rho_V}{\epsilon}$$

where V is potential per

ρ_V is charge density

ϵ is permittivity.

$\epsilon = \epsilon_0 \epsilon_r$

for Si - $\epsilon_r = 11.6$

$\epsilon_0 = 8.85 \times 10^{-12} \frac{C^2}{N \cdot m^2}$

Qb. Discretize the above equation such that finite difference method could be used to solve the same.

ANS:

Ans No. (b)

Discretization of Poisson eqn for finite difference method

$$\frac{\partial^2 V}{\partial x^2} = -\frac{\rho}{\epsilon}$$

$$= -\frac{qn_i e^{V/V_T}}{\epsilon} \quad \text{--- (1)}$$

$$\frac{dV}{dx} = \lim_{h \rightarrow 0} \frac{V(i+1/2) - V(i-1/2)}{h}$$

$$\frac{d^2 V}{dx^2} = \frac{d}{dx} \left(\frac{dV}{dx} \right) = \frac{\frac{dV}{dx} \Big|_{i+1/2} - \frac{dV}{dx} \Big|_{i-1/2}}{h}$$

$$= \frac{\left(\frac{V(i+1) - V(i)}{h} \right) - \left(\frac{V(i) - V(i-1)}{h} \right)}{h}$$

$$= \frac{V(i+1) - 2V(i) + V(i-1))}{h^2}$$

Put this eqn in eqn (1)

$$\frac{V(i+1) - 2V(i) + V(i-1))}{h^2} = -\frac{qn_i e^{V/V_T}}{\epsilon}$$

$$V(i+1) - 2V(i) + V(i-1) = -\frac{qn_i h^2 e^{V/V_T}}{\epsilon}$$

for ex: take a semiconductor with length l with end points A & B
 & also 1 volt voltage across it
 $V_A = 1, V_B = 0$
 $V(1) - V_A = 0$
 for $i=2, V(3) + V(1) - 2V(2) - \frac{qn_i h^2 e^{V(2)/V_T}}{\epsilon} = 0$
 for $i=3, V(4) + V(2) - 2V(3) - \frac{qn_i h^2 e^{V(3)/V_T}}{\epsilon} = 0$
 $V_A - V_B = 0$

Qc. List out the general form for Jacobian for the above set of equations.

ANS:

Ans No. - 4

Let for any N functions points,

$$f_1 (v_1, v_2, \dots, v_n) = 0$$

$$f_2 (v_1, v_2, \dots, v_n) = 0$$

$$\vdots$$

$$f_n (v_1, v_2, \dots, v_n) = 0$$

$$J = \begin{bmatrix} \frac{\partial f_1}{\partial v_1} & \frac{\partial f_1}{\partial v_2} & \dots & \frac{\partial f_1}{\partial v_n} \\ \frac{\partial f_2}{\partial v_1} & \frac{\partial f_2}{\partial v_2} & \dots & \frac{\partial f_2}{\partial v_n} \\ \vdots & \vdots & \ddots & \vdots \\ \frac{\partial f_n}{\partial v_1} & \frac{\partial f_n}{\partial v_2} & \dots & \frac{\partial f_n}{\partial v_n} \end{bmatrix}$$

for previous question's eqn

$$J = \begin{bmatrix} 1 & 0 & 0 & \dots & 0 \\ 1 & -2 \frac{h^2 m_1 c^2 v_1}{E v_1} & 0 & \dots & 0 \\ 0 & 1 & -2 \frac{h^2 m_2 c^2 v_2}{E v_2} & \dots & 0 \\ \vdots & \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & 0 & \dots & 1 \end{bmatrix}$$

Q d. Consider a semiconductor (say, Silicon) of thickness $200\text{ }\mu\text{m}$. Assume that one end (A) is

held at 100mV while the other (B) is held at zero potential. Using a-c given above, solve for

this system using Newton's method. Use a linearly varying potential profile as the initial guess.

Plot the potential and carrier density profiles.

ANS:

Code:

Potential:

```
clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=200*10^(-6);
ni=1.5*(10)^(16);
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
Va=0.1;
Vb=0;
V=linspace(Va,Vb,1000);
V1=V';
for i=1:1000

F(1,1)=0;
F(1000,1)=0;
for i=2:999
    F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
end

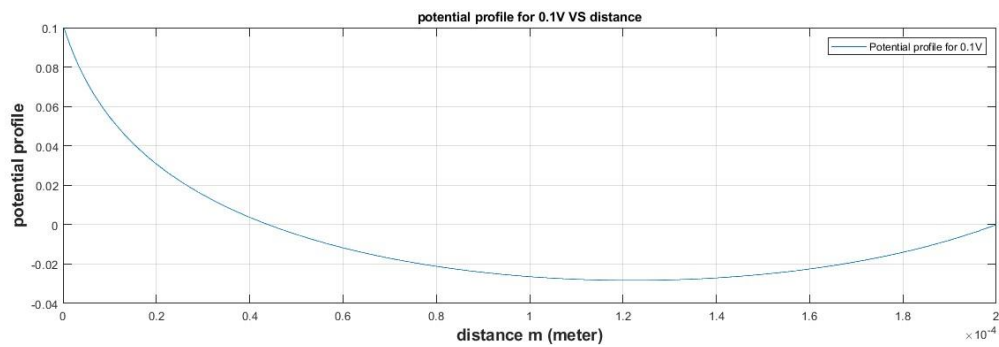
M(1,1)=1;
for i=2:1000
    M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
    M(i,i+1)=1;
end
for i=1:998
    M(i+1,i)=1;
```

```

end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%     break;
% end
V1=V2;
end
i=1:1000;
x=i*(a/1000);
plot(x,V2);

xlabel('distance ( meter)');
ylabel('potential profile(volt)');
title(' FOR 0.1V POTENTIAL PROFILE WITH RESPECT TO DISTANCE');
grid on;

```



Carrier density:

```

clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=200*10^(-6);
ni=1.5*(10)^(16);
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
Va=0.1;
Vb=0;
V=linspace(Va,Vb,1000);
V1=V';
for i=1:1000

F(1,1)=0;
F(1000,1)=0;
for i=2:999

```

```
F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));
```

```
end
```

```
M(1,1)=1;
```

```
for i=2:1000
```

```
    M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
```

```
end
```

```
for i=2:999
```

```
    M(i,i+1)=1;
```

```
end
```

```
for i=1:998
```

```
    M(i+1,i)=1;
```

```
end
```

```
M(N,N)=1;
```

```
p1=inv(M);
```

```
p2=p1*F;
```

```
V2=V1-p2;
```

```
% if abs(V2-V1)<Vt
```

```
%     break;
```

```
% end
```

```
V1=V2;
```

```
end
```

```
for i=1:1000
```

```
    n=ni*exp(V2/Vt);
```

```
end
```

```
i=1:1000;
```

```
x=i*(a/1000);
```

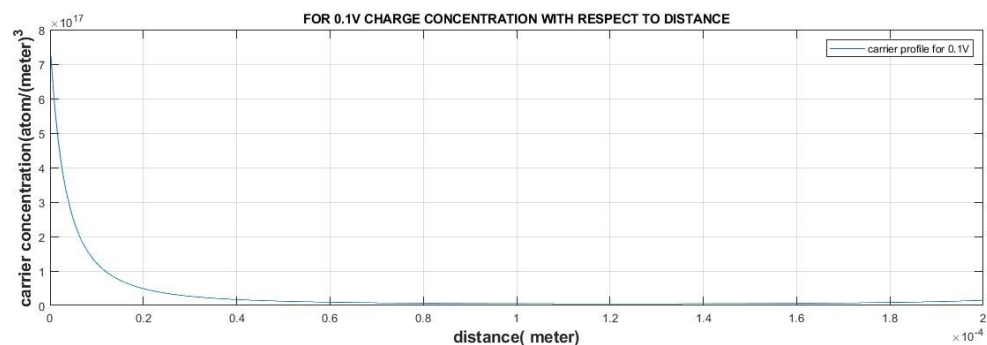
```
plot(x,n);
```

```
xlabel('distance( meter)');
```

```
ylabel('carrier concentration(atom/(meter)^3);
```

```
title('FOR 0.1V CHARGE CONCENTRATION WITH RESPECT TO DISTANCE');
```

```
grid on;
```



Qe. Repeat (d) for applied biases like 200mV, 400mV, and 600mV. Analyse your solutions.

ANS:

CODE:

Compare:

Potential:

clear all;

clc;

q=1.6*(10)^(-19);

epsilon=103.368*(10)^(-12);

a=200*10^(-6);

ni=1.5*(10)^(16);

e = 0.0001;

h=a/1000;

Vt=0.0258;

k=(q*ni*(h)^2)/epsilon;

N=1000;

for i=1:4

m=([0.1,0.2,0.4,0.6]);

Va =m(i) ;

Vb=0;

V=linspace(Va,Vb,1000);

V1=V';

for i=1:1000

F(1,1)=0;

F(1000,1)=0;

for i=2:999

F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));

end

M(1,1)=1;

for i=2:1000

M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));

end

for i=2:999

M(i,i+1)=1;

end

for i=1:998

M(i+1,i)=1;

end

M(N,N)=1;

p1=inv(M);

p2=p1*F;

V2=V1-p2;

% if abs(V2-V1)<Vt

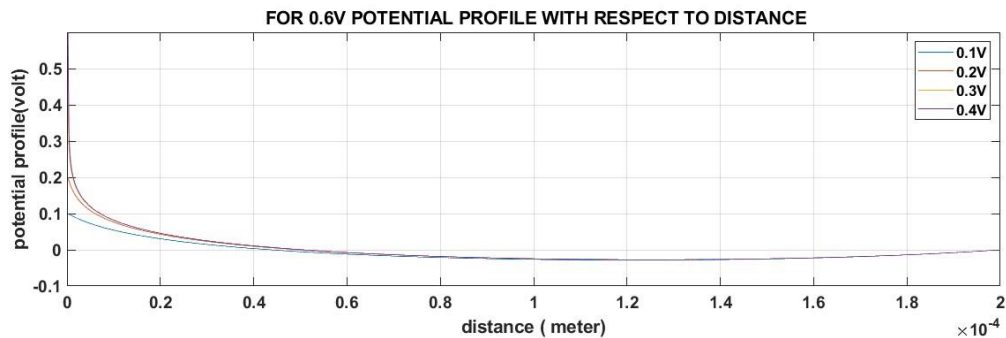
% break;


```

% end
V1=V2;
end
i=1:1000;
x=i*(a/1000);
plot(x,V2);

xlabel('distance ( meter)');
ylabel('potential profile(volt)');
title(' FOR 0.6V POTENTIAL PROFILE WITH RESPECT TO DISTANCE');
grid on;
hold on
end

```



```

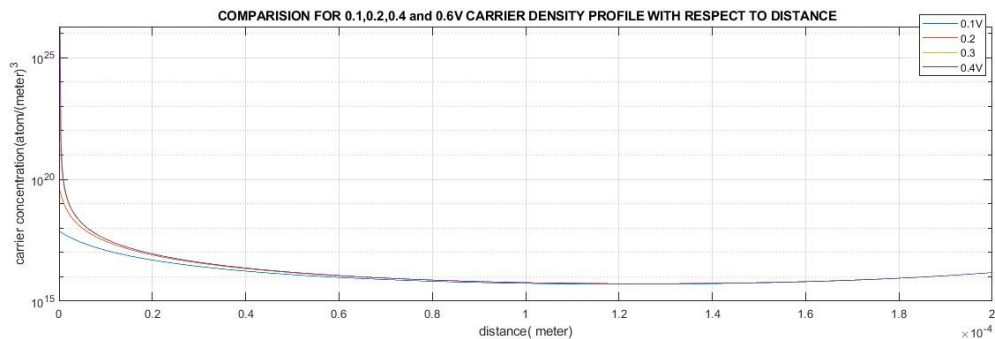
Carrier density:
clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=200*10^(-6);
ni=1.5*(10)^(16);
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
for i=1:4
m=([0.1,0.2,0.4,0.6]);
Va =m(i) ;
Vb=0;
V=linspace(Va,Vb,1000);
V1=V';
for i=1:1000

F(1,1)=0;
F(1000,1)=0;
for i=2:999
    F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));

```


end

```
M(1,1)=1;
for i=2:1000
    M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
    M(i,i+1)=1;
end
for i=1:998
    M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%     break;
% end
V1=V2;
end
for i=1:1000
    n=ni*exp(V2/Vt);
end
i=1:1000;
x=i*(a/1000);
plot(x,n);
xlabel('distance( meter)');
ylabel('carrier concentration(atom/(meter)^3)');
title(' COMPARISION FOR 0.1,0.2,0.4 and 0.6V CARRIER DENSITY PROFILE WITH RESPECT TO DISTANCE');
grid on;
hold on
end
```



Qf. Assume that SiO₂ of thickness 20nm is deposited at the end A and the potential is applied across the SiO₂ and the Semiconductor. Modify your code in (d) and find the carrier density profiles inside the semiconductor for an applied bias of 1V. Comment on your results.

ANS:

CODE

```
clear all;
clc;
q=1.6*(10)^(-19);
epsilon=103.368*(10)^(-12);
a=((200*10^(-6))-(20*10^(-9)));
ni=1.5*(10)^(16);
e = 0.0001;
h=a/1000;
Vt=0.0258;
k=(q*ni*(h)^2)/epsilon;
N=1000;
Va=1;
Vb=0;
V=logspace(Va,Vb,1000);
V1=V';
for i=1:1000

F(1,1)=0;
F(1000,1)=0;
for i=2:999
    F(i,1)=V1(i+1)+V1(i-1)-2*V1(i)-(k*exp(V1(i)/Vt));

end

M(1,1)=1;
for i=2:1000
    M(i,i)=-2-((k/Vt)*exp(V1(i)/Vt));
end
for i=2:999
    M(i,i+1)=1;
end
for i=1:998
    M(i+1,i)=1;
end
M(N,N)=1;
p1=inv(M);
p2=p1*F;
V2=V1-p2;
% if abs(V2-V1)<Vt
%     break;
```

```

% end
V1=V2;
end
for i=1:1000
    n=ni*exp(V2/Vt);
end
i=1:1000;
x=i*(a/1000);
plot(x,n);
xlabel('distance( meter)');
ylabel('carrier concentration(atom/(meter)^3)');
title('FOR 1V CHARGE CONCENTRATION WITH RESPECT TO DISTANCE');
grid on;

```

